

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

**In re the Application of:**

Sandeep Bhatia

Serial No.: 10/718,445

Filed: November 19, 2003

FOR: DUAL SCAN CHAIN DESIGN  
METHOD AND APPARATUS

Art Unit: 2117

Examiner: TABONE JR, JOHN J

Confirmation No.: 9844

**COMMENTS ON STATEMENT OF REASONS FOR ALLOWANCE**

**MAIL STOP ISSUE FEE**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Applicants wish to thank the Examiner for allowing the above-identified application.

The Examiner's Reasons for Allowance identifies numerous reasons that may relate to one or more claims. However, Applicants note that the application includes independent claims, where each independent claim may recite limitations that are different from or not present in other claims. As such, the independent claims and their respective dependent claims are allowable for what they recite.

If the Examiner has any questions or comments, the Examiner is respectfully requested to contact the undersigned at the number listed below.

Respectfully submitted,

Dated: December 17, 2009

By: /Jasper Kwoh/  
Jasper Kwoh  
Registration No. 54,921

**Vista IP Law Group LLP**

1885 Lundy Avenue,

Suite 108

San Jose, CA 95131

Telephone: (408) 321-8663